

ERRATUM

Influence of Nano Layer Interface on Space Charge Behavior and Trap Levels Using Polyimide Sandwich Structure

Shakeel Akram¹, Yan Yang¹, Xin Zhong¹, Shoaib Bhutta², Guangning Wu¹, Jerome Castellon³ and Kai Zhou⁴

¹School of Electrical Engineering Southwest Jiaotong University, Chengdu, China

²State Key Laboratory of Power Transmission Equipment, System Security & New Technology Chongqing University, Chongqing, China

³Institut d'Electronique et des Systèmes, Université de Montpellier, Montpellier, France

⁴School of Electrical Engineering and Information, Sichuan University, Chengdu, China

IEEE Trans. Dielectr. Electr. Insul., vol. 24, no. 6, pp. 3505-3514, Dec. 2017

Corrections to formatting errors in IEEE Xplore are as follows:

- 1) On page 3508, Figures 3a and 3b are duplicates; Figures 3e and 3f are duplicates.
- 2) The word Figure throughout the text is in red font which should be in black font.
- 3) On page 3514, Shakeel Akram's photo is shown as M. Shoaib Bhutta's photo; M. Shoaib Bhutta's photo is shown as Zhong Xin's photo; Zhong Xin's photo is shown as Shakeel Akram's photo.
- 4) The corrected paper appears as follows:

Influence of Nano Layer Structure of Polyimide Film on Space Charge Behavior and Trap Levels

Shakeel Akram¹, Yan Yang¹, Xin Zhong¹, Shoaib Bhutta², Guangning Wu¹, Jerome Castellon³ and Kai Zhou⁴

¹School of Electrical Engineering Southwest Jiaotong University, Chengdu, China

²State Key Laboratory of Power Transmission Equipment, System Security & New Technology Chongqing University, Chongqing, China

³Institut d'Electronique et des Systèmes, Université de Montpellier, Montpellier, France

⁴School of Electrical Engineering and Information, Sichuan University, Chengdu, China

IEEE Trans. Dielectr. Electr. Insul., vol. 25, no. 4, pp. 1461-1469, Aug. 2018